Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/622,526	HIDAKA ET AL.
Examiner	Art Unit
Dennis Myint	2162

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	3	2/27/2007	DM
715	513	2/28/2007	ÞΜ
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	2/27/2007	DM	
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	2/28/2007	DM	
NPL: GOOGLE	2/28/2007	DM	
NPL: IEEE	2/28/2007	DM	
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